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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/772,510	02/05/2004	Detlef Michelsson	21295.74 (H5742US)	5672 .
29127 HOUSTON EL	7590 02/13/2008 ISEEVA		EXAMINER	
4 MILITIA DR	IVE, SUITE 4		FUJITA, KATRINA R	
LEXINGTON,	MA 02421		ART UNIT	PAPER NUMBER
			2624	
		·	MAIL DATE	DELIVERY MODE
		•	02/13/2008	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

## Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)	Applicant(s)	
10/772,510	MICHELSSON, DETLEF	MICHELSSON, DETLEF	
Examiner	Art Unit		
Katrina Fujita	2624		

	Katrina Fujita	2624	
The MAILING DATE of this communication appe	ars on the cover sheet with the c	orrespondence add	ress
THE REPLY FILED 30 January 2008 FAILS TO PLACE THIS A			
1.  The reply was filed after a final rejection, but prior to or or this application, applicant must timely file one of the follow places the application in condition for allowance; (2) a Not a Request for Continued Examination (RCE) in compliant time periods:	the same day as filing a Notice of ving replies: (1) an amendment, aff tice of Appeal (with appeal fee) in o	Appeal. To avoid aba idavit, or other evider compliance with 37 Cl	rce, which FR 41.31; or (3)
a) The period for reply expires <u>3</u> months from the mailing date	of the final rejection.		
b) The period for reply expires on: (1) the mailing date of this A no event, however, will the statutory period for reply expire to	ater than SIX MONTHS from the mailing	g date of the final rejection	on.
Examiner Note: If box 1 is checked, check either box (a) or TWO MONTHS OF THE FINAL REJECTION. See MPEP 7	06.07(f).		
Extensions of time may be obtained under 37 CFR 1.136(a). The date have been filed is the date for purposes of determining the period of ex under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	tension and the corresponding amount shortened statutory period for reply origing than three months after the mailing data.	of the fee. The appropri inally set in the final Office	ate extension fee be action; or (2) as
<ol> <li>The Notice of Appeal was filed on A brief in comp filing the Notice of Appeal (37 CFR 41.37(a)), or any exte a Notice of Appeal has been filed, any reply must be filed</li> </ol>	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of th	s of the date of e appeal. Since
AMENDMENTS  3. The proposed amendment(s) filed after a final rejection, (a) They raise new issues that would require further co			ecause
<ul> <li>(b) They raise the issue of new matter (see NOTE below)</li> <li>(c) They are not deemed to place the application in below</li> </ul>	w);		the issues for
appeal; and/or (d) They present additional claims without canceling a NOTE: (See 37 CFR 1.116 and 41.33(a)).	corresponding number of finally rej	ected claims.	
4. The amendments are not in compliance with 37 CFR 1.1	21. See attached Notice of Non-Co	mpliant Amendment (	PTOL-324).
5. Applicant's reply has overcome the following rejection(s)	:		
<ol> <li>Newly proposed or amended claim(s) would be all non-allowable claim(s).</li> </ol>	lowable if submitted in a separate,	timely filed amendme	nt canceling the
7.  For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is protected. The status of the claim(s) is (or will be) as follows:	will not be entered, or b)      will will not be entered, or b)      will will not be entered, or b)      will not be entered.       will not be entered, or b)      will not be entered.        will not be entered.        will not be entered.        will not be entered.        will not be entered.        will not be entered.         will not be entered.	l be entered and an e	xplanation of
Claim(s) allowed: <u>None</u> . Claim(s) objected to: <u>None</u> .			
Claim(s) rejected: 3-16 and 27-34.			
Claim(s) withdrawn from consideration: <i>None</i> . AFFIDAVIT OR OTHER EVIDENCE			
8.  The affidavit or other evidence filed after a final action, but	t before or on the date of filing a No	otice of Appeal will no	t be entered
because applicant failed to provide a showing of good an was not earlier presented. See 37 CFR 1.116(e).	d sufficient reasons why the affidav	it or other evidence is	necessary and
9. The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to of showing a good and sufficient reasons why it is necessar	vercome <u>all</u> rejections under appear y and was not earlier presented. S	al and/or appellant fai ee 37 CFR 41.33(d)(1	ls to provide a ).
10. ☐ The affidavit or other evidence is entered. An explanatio REQUEST FOR RECONSIDERATION/OTHER	n of the status of the claims after er	ntry is below or attach	ed.
<ol> <li>The request for reconsideration has been considered bu See attachment.</li> </ol>	t does NOT place the application in	condition for allowar	pee because)
12. Note the attached Information Disclosure Statement(s).	(PTO/SB/08) Paper No(s)		///
13. Other:			Mi

KJ

VIKKRAM BALI PRIMARY EXAMINER Application/Control Number: 10/772,510

Art Unit: 2624

Attachment for Advisory Action, Paper No. 20080211

## Response to Arguments

Summary of Remarks (@ response page labeled 9): "The segmentation suggested by Shibata has nothing to do with the segmentation in order to achieve the same image content after a certain number of captured image fields."

Examiner's Response: Disagreed. As the Examiner pointed out in the Office Action, each die contains the same pattern and as such, as each die is separated into segments, the same image content would be attained at each die.

Summary of Remarks (@ response page labeled 9): "Shibata does not show the allocation of logical SAW-segments to the image field segments."

Examiner's Response: The die is broken into segments as addressed above and each conditioning image is broken into regions as cited in the Office Action ("detected image is divided into regions of predetermined size" at paragraph 0044, line 2).

Therefore, the image field segments and logical SAW segments are allocated to each other for each die and are thus identical as subsequent dies are imaged since each die contains the same pattern.

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Summary of Remarks (@ response page labeled 9): The Shibata reference discloses comparing adjacent chips with each other, which is not the case with Applicant's invention, which compares image field segments which have the same content.

Examiner's Response: As adjacent chips are compared with each other in the Shibata reference and each chip, or die, contains the same pattern and accordingly divided into segments the same as described above, comparison is done between image field segments that have the same content.

Summary of Remarks (@ response page labeled 9): The Shibata reference does not take "into account the fact that the size of the SAWs varies greatly depending on the stepper and die size (design)."

Examiner's Response: This particular aspect upon which applicant relies is not recited in the rejected claims. Although the claims are interpreted in light of the specification, limitations from the specification are not read into the claims. See In re Van Geuns, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993).

Summary of Remarks (@ response page labeled 9): The Park reference does not disclose "as the camera travels over the wafer an identical allocation of logical SAW segments to image field segments".

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Examiner's Response: This argument was previously addressed in the Final Office Action and will not be repeated herein.

Summary of Remarks (@ response page labeled 9): A person skilled in the art would not consider the Park reference.

Examiner's Response: As stated in the Office Action, the Park reference is indeed analogous art as it describes "a system in the same field of endeavor of wafer defect inspection" at Office Action, page 6. The Examiner also provided motivation for combining the teachings of the Park reference with the Shibata reference at page 7 of the Office Action.